
4.5 mm STRADA Whisper* Connector System

1. SCOPE**1.1. Content**

This specification defines performance, tests and quality requirements for the STRADA WHISPER Connector System that uses a modular concept to interconnect two printed circuit boards. Both receptacle and pin connectors are connected to the printed circuit board with plated thru-hole compliant press-fit leads.

1.2. Qualification

When tests are performed on the subject product line, procedures specified in Figure 1 shall be used. All inspections shall be performed using the applicable inspection plan and product drawing.

1.3. Qualification Test Results

Successful qualification testing on the subject product line was completed on 15Aug2012. The Qualification Test Report number for this testing is 501-134007.

2. APPLICABLE DOCUMENTS AND FORMS

The following documents and forms constitute a part of this specification to the extent specified herein. Unless otherwise indicated, the latest edition of the document applies.

2.1. TE Documents

- [114-13301](#): 4.5 mm STRADA Whisper Connector System
- [501-134007](#): 4.5 mm STRADA Whisper Connector System

2.2. Industry Documents

- EIA-364: Electrical Connector/Socket Test Procedures Including Environmental Classifications

2.3. Reference Document

- [109-197](#) Test Specification (TE Test Specification vs EIA and IEC Test Methods)

3. REQUIREMENTS**3.1. Design and Construction**

Product shall be of the design, construction, materials and physical dimensions specified on the applicable product drawing.

3.2. Ratings

Voltage	Current	Temperature
250 volts AC maximum peak ($\frac{1}{3}$ of minimum breakdown voltage)	0.5 ampere per signal contact (fully loaded)	-55° to 85°C (Operating and Storage)

3.3. Test Requirements and Procedures Summary

Unless otherwise specified, all tests shall be performed at ambient environmental conditions.

Test Description	Requirement	Procedure
Initial examination of product.	Meets requirements of product drawing and Application Specification 114-13301.	EIA-364-18. Visual and dimensional (C of C) inspection per product drawing.
Final examination of product.	Meets visual requirements.	EIA-364-18. Visual inspection.
ELECTRICAL		
Low Level Contact Resistance (LLCR).	100 milliohms maximum initial. ΔR 10 milliohms maximum individual signal reading final and ΔR 20 milliohms maximum individual ground reading final.	EIA-364-23. Subject specimens to 100 milliamperes maximum and 20 millivolts maximum open circuit voltage.
Low Level Compliant Pin Resistance (LLCPR).	1 milliohm maximum initial. ΔR 1 milliohm maximum change from initial.	EIA-364-23. Subject specimens to 100 milliamperes maximum and 20 millivolts maximum open circuit voltage. Measurements shall be taken between PCB hole and pin tip.
Insulation resistance.	1000 megohms minimum.	EIA-364-21. 100 volts DC, 2 minute hold. Test between adjacent contacts of mated specimens.
Withstanding voltage.	One minute hold with no breakdown or flashover.	EIA-364-20, Condition I. 560 volts AC maximum peak at sea level. Test between adjacent contacts of mated specimens.
Temperature rise vs. current.	30°C maximum temperature rise at .5 ampere per signal contact, fully energized.	EIA-364-70, Method 1. Stabilize at a single current level until 3 readings at 5 minute intervals are within 1°C.
MECHANICAL		
Random vibration.	No discontinuities of 1 microsecond or longer duration. See Note.	EIA-364-28, Test Condition VII, Condition D. Subject mated specimens to 3.10 G's rms between 20 to 500 Hz. Fifteen minutes in each of 3 mutually perpendicular planes.
Mechanical shock.	No discontinuities of 1 microsecond or longer duration. See Note.	EIA-364-27, Method A. Subject mated specimens to 490m/s ² (50 G's) half-sine shock pulses of 11 milliseconds duration. Three shocks in each direction applied along 3 mutually perpendicular planes, 18 total shocks.
Durability.	See Note.	EIA-364-9. Mate and unmate specimens for 200 cycles at a maximum rate of 600 cycles per hour.
Mating force.	1.82 N [0.41 lbf] maximum average per differential pair including ground.	EIA-364-13. Measure force necessary to mate specimens at a maximum rate of 12.7 mm [.5 in] per minute.

Test Description	Requirement	Procedure
Unmating force.	0.31 N [.07 lbf] minimum average per differential pair including ground.	EIA-364-13. Measure force necessary to unmate specimens at a maximum rate of 12.7 mm [.5 in] per minute.
Compliant pin insertion force.	33.5 N [7.5 lbf] maximum average per pin.	EIA-364-5. Measure force necessary to seat pins into a printed circuit board with immersion tin plating at a maximum rate of 12.7 mm [.5 in] per minute.
Compliant pin retention force.	0.89 N [0.20 lbf] minimum average per pin.	EIA-364-5. Measure force necessary to unseat pins from a printed circuit board with immersion tin plating at a maximum rate of 12.7 mm [.5 in] per minute.
Minute disturbance.	See Note.	Unmate and mate each connector pair a distance of approximately 0.1 mm [.004 in].

ENVIRONMENTAL

Thermal shock.	See Note.	EIA-364-32, Method A, Test Condition I. Subject mated specimens to 5 cycles between -55 and 85°C with 30 minute dwells at temperature extremes and 1 minute transition between temperatures.
Humidity/temperature cycling.	See Note.	EIA-364-31, Method III. Subject mated specimens to 50 cycles (800 hours) between 5 and 85°C at 80 to 100% RH.
Temperature life.	See Note.	EIA-364-17, Method A, Test Time Condition C. Subject mated specimens to 90°C for 500 hours.
Mixed flowing gas.	See Note.	EIA-364-65, Class IIA (4 gas). Subject specimens to environmental Class IIA for 20 days total (10 days unmated followed by 10 days mated).
Dust contamination.	See Note.	EIA-364-91. Subject unmated specimens to dust contamination #1 for 1 hour. Air flow shall be 360 cfm.



NOTE

Shall meet visual requirements, show no physical damage, and meet requirements of additional tests as specified in the Product Qualification and Requalification Test Sequence shown in Figure 2.

3.4. Product Qualification and Requalification Test Sequence

Test or Examination	Test Group (a)					
	1	2	3	4	5	6
	Test Sequence (b)					
Initial examination of product	1	1	1	1	1	1
LLCR	3,6,8,10,12	3,5,7,9,11		4 (c),6	2,4,6,8,10,12,14,16	
LLCPR		2,12		3,7		
Insulation resistance			6			
Withstanding voltage			7			
Temperature rise vs. current						2
Vibration	9					
Mechanical shock	11					
Durability	5	4	2		3 (d),15 (d)	
Mating force	2,14					
Unmating force	4,13					
Compliant pin insertion force				2		
Compliant pin retention force				8		
Minute disturbance					13	
Thermal shock		8	4			
Humidity/temperature cycling		10	5			
Temperature life				5		
Mixed flowing gas (mated)					9 (e),11 (e)	
Mixed flowing gas (unmated)					5 (e),7 (e)	
Dust contamination	7	6	3			
Final examination of product	15	13	8	9	17	3



NOTE

- Specimens shall be prepared in accordance with applicable Instruction Sheets and shall be selected at random from current production. Each test group shall consist of a minimum of 3 specimens.
- Numbers indicate sequence in which tests are performed.
- Perform 10 durability cycles prior to initial measurement.
- Perform 100 durability cycles before, and 100 durability cycles after mixed flowing gas testing.
- Exposure interval of 5 days.